

Preliminary

## Contact Image Sensor (CIS) Module

Product Name

**M208-A8**

Approval		Notes		
<b>CMOS Sensor Inc.</b> 20045 Stevens Creek Blvd., Suite 1A Cupertino, CA., 95014 Tel: (408) 366-2898 Fax: (408) 366-2698		Approved	Checked	Designed
Issued		Revision no.		
All specifications of this device are subject to change without notice.				

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## Revision control sheet

Revision No.	Date	Item of change and content	Reason	Approved	Designed

# CMOS Sensor Inc.

## M208-A8 600 dpi Compact Image Sensor (CIS) module

### Feature:

- 1344 x 1 image sensing elements
- 600 (dpi) resolution
- 56 mm scanning length
- 15 mm x 15 mm x 70 mm compact size
- Better than 5Mhz pixel output rate
- LED light source
- high MTF
- light weight
- single 5 V power supply
- low power consumption
- high dynamic range > 1000
- high integration for light source, lens and sensor
- 8 pin connector for input and output

### Description:

The M208-A8 compact image sensor module is a contact type image sensing module that composes of a line of LED light source, a long Selfoc rod lens array, and 1344 pixels of photo-detector array. Input and output electronic contact is via a 8-pin connector. The cross section view and functional block diagram of the M208-A8 is shown in figure 1 and figure 2, respectively.

The module is suitable to scan an A8 size (56 mm) document. Applications include fax machine, document scanner, mark reader, and other office automation equipment.

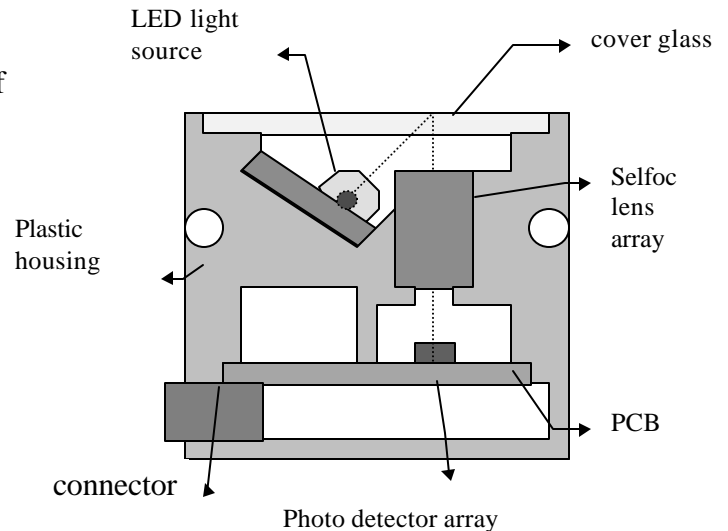


Figure 1. Cross section view of M208-A8.

## Functional block diagram:

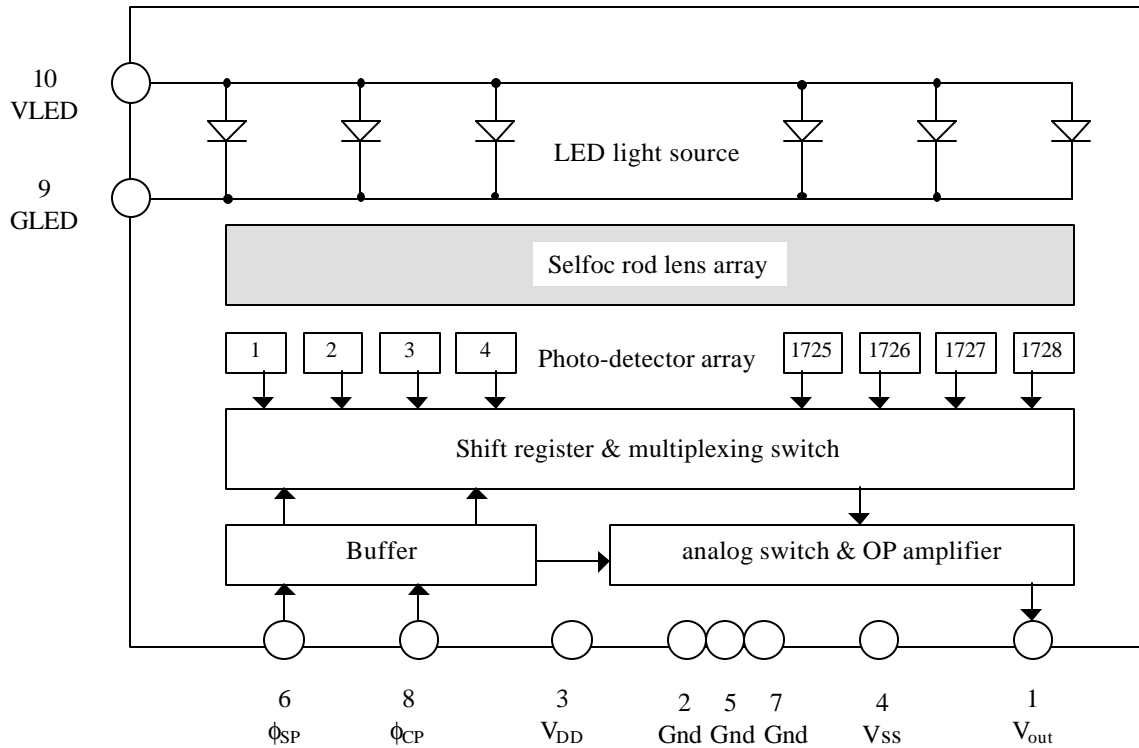


Figure 2 Functional block diagram of M100-A6.

## Pins Description:

Pin #	Symbol	Description
1	VOUT	Output video signal
2	GND	Ground 0V
3	VDD	Module power supply voltage (+5V)
4	SP	Start pulse input
5	VREF	Reference voltage (input)
6	CP	Clock pulse input
7	GLED	LED power supply ground; 0V
8	VLED	LED power supply voltage; 5 V

## Electro-optical characteristics:

at  $f = 500 \text{ kHz}$ ,  $V_{DD} = 5 \text{ V}$ ,  $T_{int}^{*(1)} = 5 \text{ ms}$ ,  $\lambda^{*(2)} = 570 \text{ nm}$ ,  $T_a^{*(3)} = 25 \text{ }^\circ\text{C}$   
(unless otherwise noted)

symbol	Parameter	test conditions	min.	typ	max	unit
$V_p^{*(4)}$	Analog output voltage at white paper	O.D. <sup>*(11)</sup> = 0.05 ~ 0.1	1.4	1.6	1.8	V
$U_p^{*(5)}$	White paper non-uniformity	O.D. = 0.05 ~ 0.1	-30		30	%
$U_{p\text{adj}}^{*(6)}$	Adjacent pixel non-uniformity	O.D. = 0.05 ~ 0.1	-25		25	%
$V_d^{*(7)}$	Analog output voltage at dark paper	light off, O.D. = 0.8	-100		+100	mV
$U_d^{*(8)}$	Dark signal non-uniformity	light off, O.D. = 0.8			200	mV
MTF <sup>*(9)</sup>	Modulation transfer function	at 3.85 lp/mm <sup>*(12)</sup>	30			%
$\gamma^{*(10)}$	Linearity		0.85		1.1	

### Definition:

- $T_{int}$  is an integration time. It is determined by the internal of two start pulses.
- $\lambda$  is a wavelength of the light source.
- $T_a$  is ambient temperature.
- $V_p = (V_{p\text{max}} + V_{p\text{min}}) / 2$   
where  $V_{p\text{max}}$  is a maximum voltage of whole module on white document.  
 $V_{p\text{min}}$  is a minimum voltage of whole module on white document.
- $U_p$  is a pixel - pixel photo response non-uniformity within whole module.  
 $U_p = [(V_{p\text{max}} - V_{p\text{min}}) / V_p] \times 100\%$
- $U_{p\text{adj}} = \text{Max} [|(V_p(i) - V_p(i+1)) / V_p(i)| \times 100\%]$   
where  $V_p(i)$  is the video signal output of each pixel #  $i$   
 $V_p(i+1)$  is the video signal output of each pixel #  $(i+1)$
- $V_d = (V_{d\text{max}} + V_{d\text{min}}) / 2$   
where  $V_{d\text{max}}$  is a maximum dark signal on whole module.  
 $V_{d\text{min}}$  is a minimum dark voltage on whole module.
- $U_d = V_{d\text{max}} - V_{d\text{min}}$
- $\text{MTF} = [(V_{\text{max}} - V_{\text{min}}) / (V_{\text{max}} + V_{\text{min}})] \times 100\%$   
where  $V_{\text{max}}$  is the maximum output voltage at 3.85 lp/mm document.  
 $V_{\text{min}}$  is the minimum output voltage at 3.85 lp/mm document.
- $\gamma = \log[(V_2 - V_d) / (V_1 - V_d)] / \log(E_2/E_1)$  or  $\log[(V_2 - V_d) / (V_1 - V_d)] / \log(T_2/T_1)$   
where  $V_1$  is the output voltage of  $E_1$  illumination or  $T_1$  integration time  
 $V_2$  is the output voltage of  $E_2$  illumination or  $T_2$  integration time  
at 10 ~ 90% of saturation conduction.
- O.D. = optical density of the paper.
- lp / mm = line pair per millimeter

## Absolute maximum ratings:

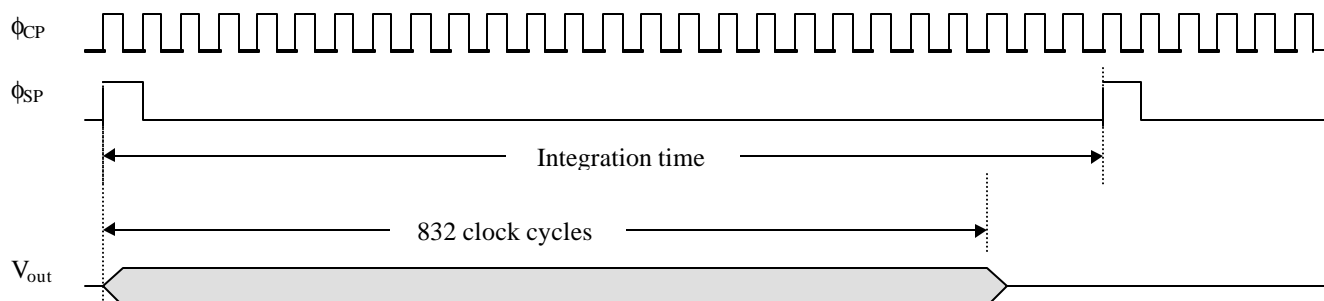
Parameter Name	Symbol	Max Value	Units
Power supply voltage	V <sub>DD</sub>	6	V
Power supply current	I <sub>DD</sub>	40	mA
LED light power supply voltage	V <sub>LED</sub>	7	V
LED light power supply current	I <sub>LED</sub>	60	mA
Digital input voltage range high	V <sub>IH</sub>	5.5	V
Digital input voltage range low	V <sub>IL</sub>	-0.5	V
Operating temperature	T <sub>a</sub>	0 ~ 50	C
Storage temperature	T <sub>stg</sub>	-25 ~ 70	C

⚠ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress rating only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## Recommend operating conditions:

Item	Symbol	Min.	Typ.	Max.	Unit
Positive power supply voltage	V <sub>DD</sub>	4.75	5	5.25	V
Negative power supply voltage	V <sub>SS</sub>	- 11	- 12	-13	V
LED power supply voltage	V <sub>LED</sub>		2.1		V
High level input voltage	V <sub>IH</sub>	V <sub>DD</sub> -0.7		V <sub>DD</sub>	V
Low level input voltage	V <sub>IL</sub>	0		0.7	V
Clock frequency	CP	0.5	1.0	1.5	MHz
Pixel output frequency	F	1.0	2.0	3.0	MHz
Clock pulse high duration	T <sub>w</sub>		0.5	1.0	us
Wavelength of light source	λ		570		nm
Operating free-air temperature	T <sub>a</sub>	0	25	50	°C

## Timing Diagram:



## PRODUCT RELIABILITY TESTS

Items of Test	Testing Conditions	Inspection items	Pass Criteria
Life Test	Temp = $25 \pm 5$ °C,	$\Delta V_p, \Delta V_d$ : the change of $V_p, V_d$ respectively after the life testing.	-30 % < $\Delta V_p$ < 10 % -25 mV < $\Delta V_d$ < 15mV
	Humidity = 20 ~ 80 RH%		
	Time = 2000 hrs		
High Temp Test	Temp = $80 \pm 5$ °C	electrical parameters, module structures.	Parameters must be within specs, no change, no damage in module structures
	Time = 144 hrs		
Low Temp Test	Temp = $-30 \pm 5$ °C		
	Time = 144 hrs		
Temp/Humidity Test	Temp = $50 \pm 5$ °C,	$\Delta V_p$ : the change of $V_p$ after the life testing.	-30% < $\Delta V_p$ < 10%
	Humidity = $85 \pm 5$ RH%		
	Time = 144 hrs		
Temp Cycling	Temp = -30, 25, 80 °C	Electrical parameters, Module structures.	All electrical parameters must be within the specs. No distortion and damage on module.
	Time = 30, 5, 30 min.		
	Cycles = 10, 50		
Drop Test	Packaged product drops from 1 m height.		
	Perform test for 3 sides.		
Vibration Test	Cycling: 10 ~ 50 ~ 10 Hz		
	Cycle time = 1 min		
	Amp = 2 mm, Time = 1 Hr		

### Precautions before use:

#### 1. Dirty Glass Surface:

The glass surface should be kept clean.

Do not wipe the sensor by hand or use in a dust polluted environment. Should the glass surface become dirty, soak a cloth lightly alcohol and wipe the surface gently.

Care should be taken so as not to scratch the surface while wiping it. Any loose dust lying on the sensor surface can be cleaned using an air gun.

#### 2. Dust and the CIS unit

The unit is housed in an air tight structure to protect it from dust. The side plates should be removed, otherwise dust may enter the unit. When using the side holes to fix the sensor, insert the screws slowly until tight, so as not to damage the screw hole thread.

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### 3. Extracting / Inserting the connector

The maximum number of times that the connector should be extracted and connected is ten. If the connector is inserted / extracted more than ten times, the connector “burrs” will be eroded, thereby making the connector ineffective.

### 4. Stable operation

4.1 The connector pins should not be touched by bare hand or Electro-statically charged material.

#### 4.2 Noise:

- a. Insert a low frequency noise suppressing capacitor (100  $\mu$ F) between  $V_{DD}$  (+5 V) and Gnd. A high frequency noise suppressing capacitor is already integrated into the circuit.
- b. Ensure that the sensor connecting cables are 30 cm or less in length. The  $\phi_{CP}$  and Gnd,  $\phi_{SP}$  and Gnd respectively from twisted cable pairs.

#### 4.3 Latch Up

When the voltage is higher than the absolute maximum, “latch up” will cause the sensor to break, even if the voltage is caused by a surge. If the current varies rapidly in the external circuit, or when the power is turned off and then on again, ensure that the voltage on each terminal does not exceed the values indicated in “absolute maximum rating”.

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